

## General Description

The AO3422 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. It offers operation over a wide gate drive range from 2.5V to 12V. This device is suitable for use as a load switch.

## Features

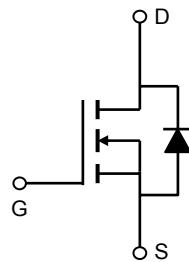
$V_{DS}$  (V) = 55V

$I_D$  = 2.1A ( $V_{GS}$  = 4.5V)



$R_{DS(ON)} < 160\text{m}\Omega$  ( $V_{GS}$  = 4.5V)

$R_{DS(ON)} < 200\text{m}\Omega$  ( $V_{GS}$  = 2.5V)



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter                              | Symbol                 | Maximum    |  | Units |
|--|------------------------|------------|--|-------|
| Drain-Source Voltage                   | $V_{DS}$               | 55         |  | V     |
| Gate-Source Voltage                    | $V_{GS}$               | $\pm 12$   |  | V     |
| Continuous Drain Current <sup>A</sup>  | $T_A=25^\circ\text{C}$ | 2.1        |  | A     |
| Current <sup>A</sup>                   |                        | 1.7        |  |       |
| Pulsed Drain Current <sup>B</sup>      | $I_{DM}$               | 10         |  |       |
| Power Dissipation                      | $T_A=25^\circ\text{C}$ | 1.25       |  | W     |
|  |                        | 0.8        |  |       |
| Junction and Storage Temperature Range | $T_J, T_{STG}$         | -55 to 150 |  | °C    |

### Thermal Characteristics

| Parameter                                | Symbol              | Typ | Max | Units |
|--|---------------------|-----|-----|-------|
| Maximum Junction-to-Ambient <sup>A</sup> | $t \leq 10\text{s}$ | 75  | 100 | °C/W  |
| Maximum Junction-to-Ambient <sup>A</sup> |                     | 115 | 150 | °C/W  |
| Maximum Junction-to-Lead <sup>C</sup>    | $R_{0JL}$           | 48  | 60  | °C/W  |

Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

| Symbol                      | Parameter                             | Conditions   | Min | Typ  | Max       | Units            |
|-----------------------------|---------------------------------------|--|-----|------|-----------|------------------|
| <b>STATIC PARAMETERS</b>    |                                       |  |     |      |           |                  |
| $\text{BV}_{\text{DSS}}$    | Drain-Source Breakdown Voltage        | $I_D=10\text{mA}$ , $V_{GS}=0\text{V}$   | 55  |      |           | V                |
| $I_{\text{DSS}}$            | Zero Gate Voltage Drain Current       | $V_{DS}=44\text{V}$ , $V_{GS}=0\text{V}$<br>$T_J=55^\circ\text{C}$                         |     |      | 1<br>5    | $\mu\text{A}$    |
| $I_{\text{GSS}}$            | Gate-Source leakage current           | $V_{DS}=0\text{V}$ , $V_{GS}=\pm 12\text{V}$   |     |      | $\pm 100$ | nA               |
| $V_{GS(\text{th})}$         | Gate Threshold Voltage                | $V_{DS}=V_{GS}$ $I_D=250\mu\text{A}$   | 0.6 | 1.3  | 2         | V                |
| $I_{D(\text{ON})}$          | On state drain current                | $V_{GS}=4.5\text{V}$ , $V_{DS}=5\text{V}$  | 10  |      |           | A                |
| $R_{DS(\text{ON})}$         | Static Drain-Source On-Resistance     | $V_{GS}=4.5\text{V}$ , $I_D=2.1\text{A}$<br>$T_J=125^\circ\text{C}$                        |     | 125  | 160       | $\text{m}\Omega$ |
|                             |                                       | $V_{GS}=2.5\text{V}$ , $I_D=1.5\text{A}$   |     | 175  | 210       | $\text{m}\Omega$ |
| $g_{FS}$                    | Forward Transconductance              | $V_{DS}=5\text{V}$ , $I_D=2.1\text{A}$   |     | 11   |           | S                |
| $V_{SD}$                    | Diode Forward Voltage                 | $I_S=1\text{A}$  |     | 0.78 | 1         | V                |
| $I_S$                       | Maximum Body-Diode Continuous Current |  |     |      | 1         | A                |
| <b>DYNAMIC PARAMETERS</b>   |                                       |  |     |      |           |                  |
| $C_{iss}$                   | Input Capacitance                     | $V_{GS}=0\text{V}$ , $V_{DS}=25\text{V}$ , $f=1\text{MHz}$                                 |     | 214  | 300       | pF               |
| $C_{oss}$                   | Output Capacitance                    |  |     | 31   |           | pF               |
| $C_{rss}$                   | Reverse Transfer Capacitance          |  |     | 12.6 |           | pF               |
| $R_g$                       | Gate resistance                       | $V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $f=1\text{MHz}$                                  |     | 1.3  | 3         | $\Omega$         |
| <b>SWITCHING PARAMETERS</b> |                                       |  |     |      |           |                  |
| $Q_g$                       | Total Gate Charge                     | $V_{GS}=4.5\text{V}$ , $V_{DS}=27.5\text{V}$ , $I_D=2.1\text{A}$                           |     | 2.6  | 3.3       | nC               |
| $Q_{gs}$                    | Gate Source Charge                    |  |     | 0.6  |           | nC               |
| $Q_{gd}$                    | Gate Drain Charge                     |  |     | 0.8  |           | nC               |
| $t_{D(\text{on})}$          | Turn-On Delay Time                    | $V_{GS}=10\text{V}$ , $V_{DS}=27.5\text{V}$ , $R_L=12\Omega$ ,<br>$R_{\text{GEN}}=3\Omega$ |     | 2.3  |           | ns               |
| $t_r$                       | Turn-On Rise Time                     |  |     | 2.4  |           | ns               |
| $t_{D(\text{off})}$         | Turn-Off Delay Time                   |  |     | 16.5 |           | ns               |
| $t_f$                       | Turn-Off Fall Time                    |  |     | 2    |           | ns               |
| $t_{rr}$                    | Body Diode Reverse Recovery Time      | $I_F=2.1\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$  |     | 20   | 30        | ns               |
| $Q_{rr}$                    | Body Diode Reverse Recovery Charge    | $I_F=2.1\text{A}$ , $dI/dt=100\text{A}/\mu\text{s}$  |     | 17   |           | nC               |

A: The value of  $R_{\text{0JA}}$  is measured with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

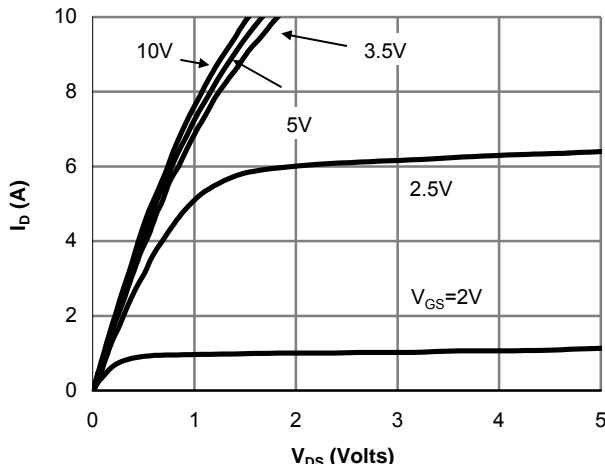
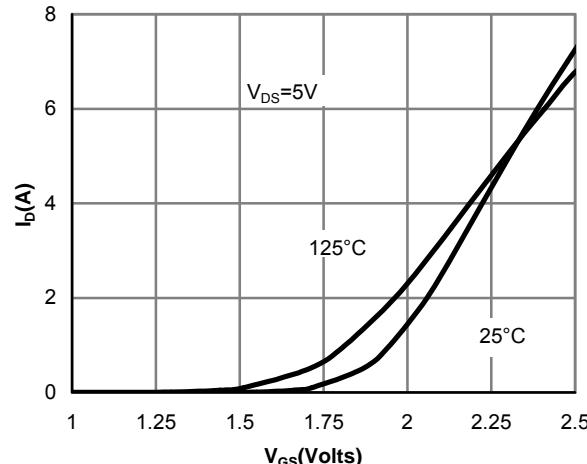
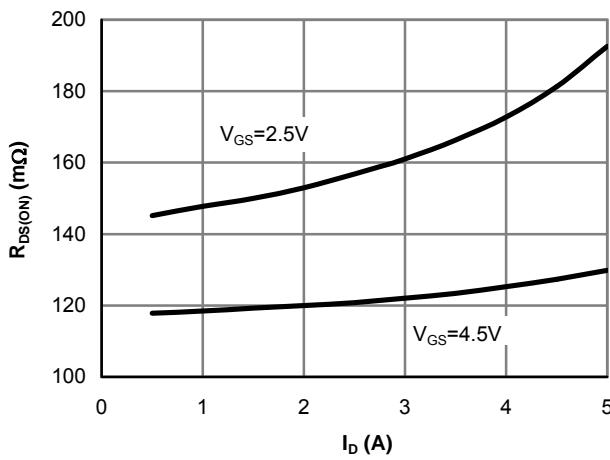
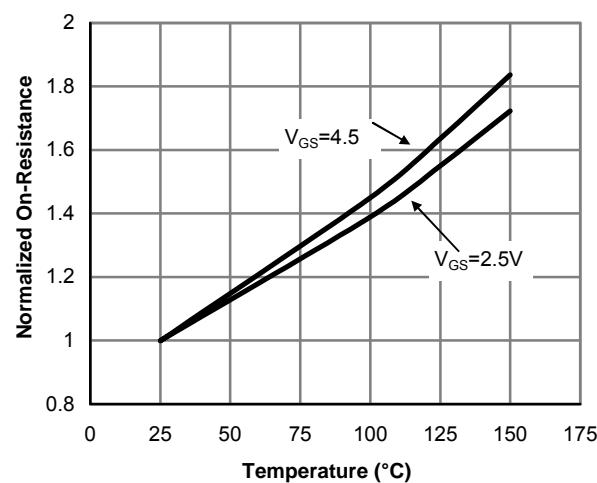
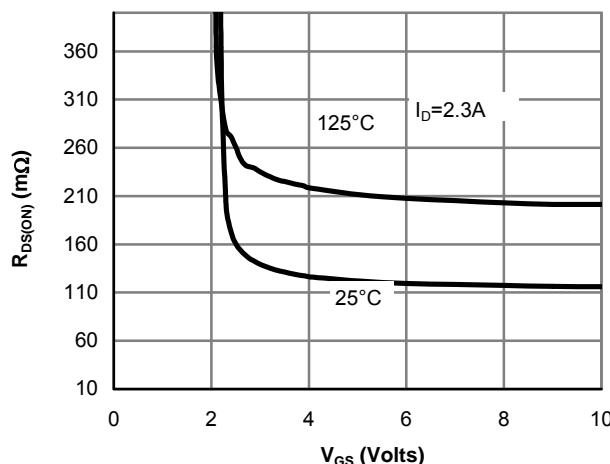
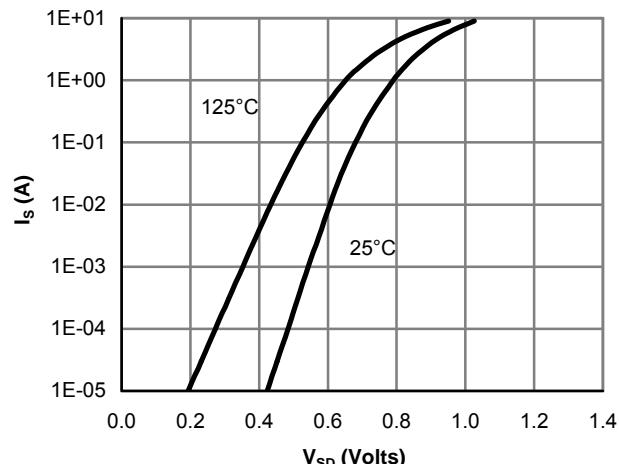
C. The  $R_{\text{0JA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{0JL}}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300  $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in  $^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region characteristics**

**Figure 2: Transfer Characteristics**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4: On-Resistance vs. Junction Temperature**

**Figure 5: On-Resistance vs. Gate-Source Voltage**

**Figure 6: Body-Diode Characteristics**

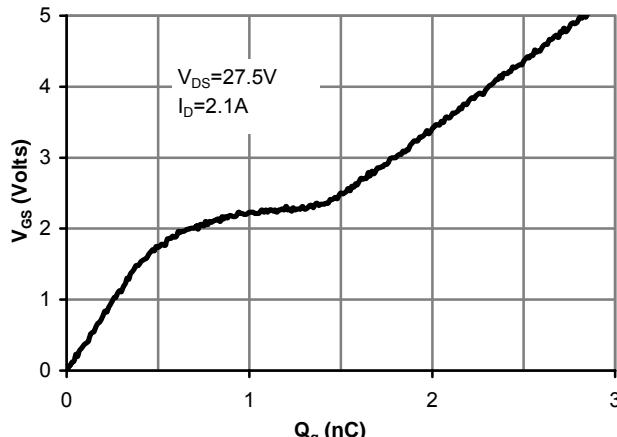
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

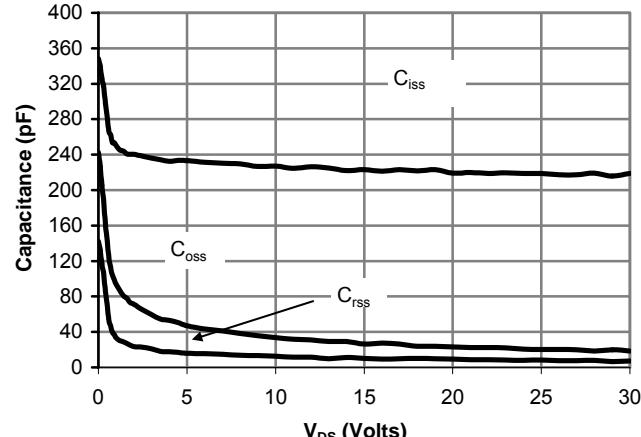


Figure 8: Capacitance Characteristics

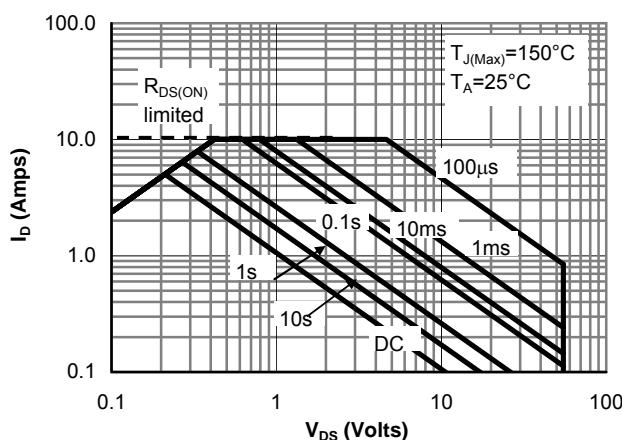
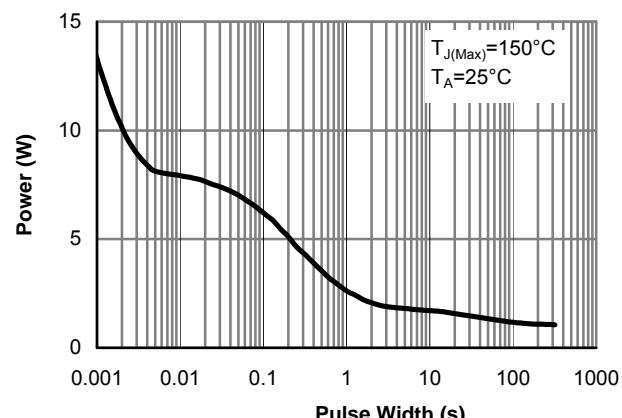

 Figure 9: Maximum Forward Biased Safe  
 Operating Area (Note E)


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

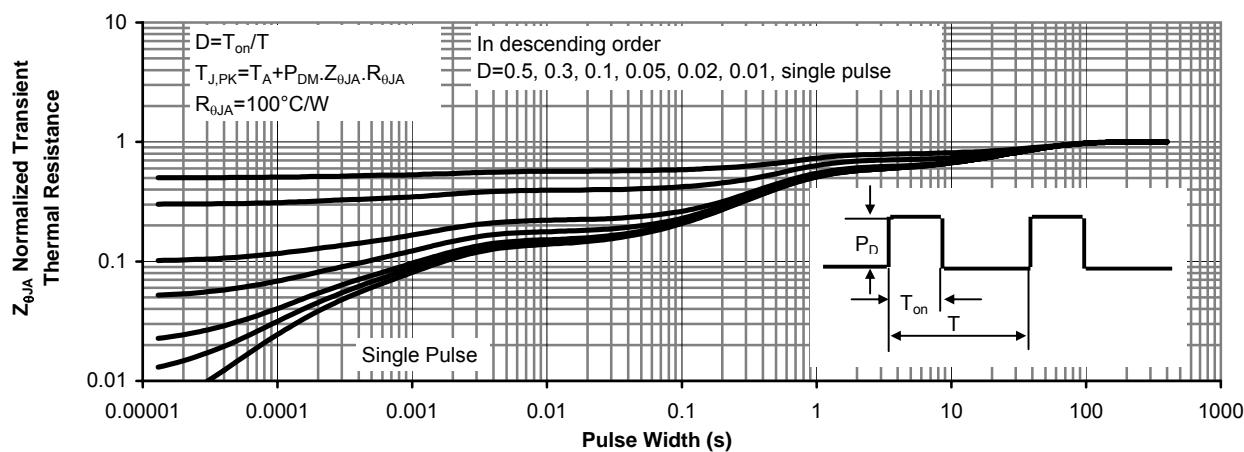
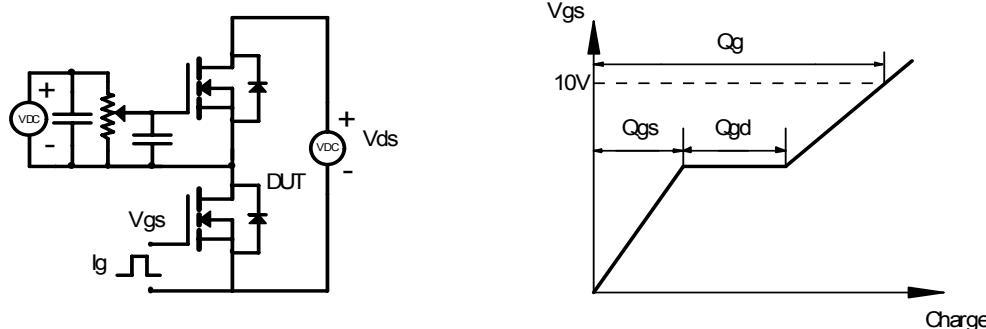
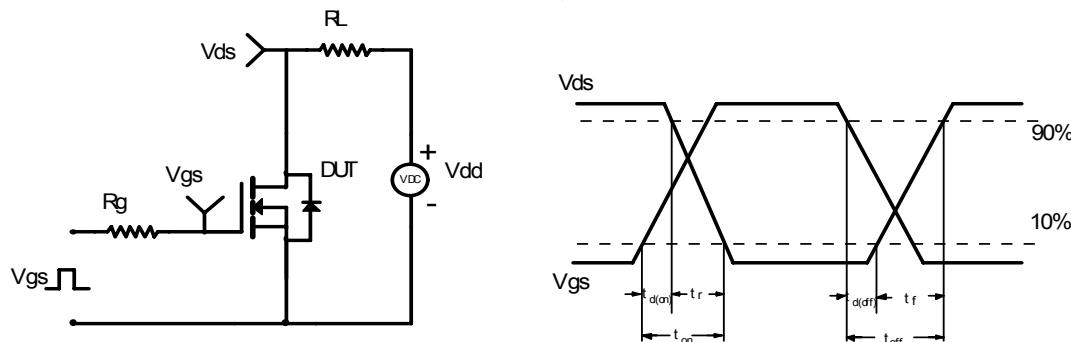


Figure 11: Normalized Maximum Transient Thermal Impedance

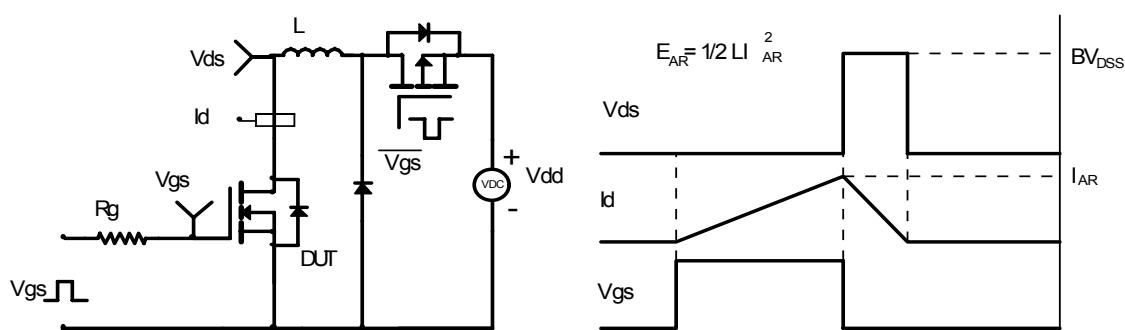
Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveforms



Unclamped Inductive Switching (UIS) Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms

